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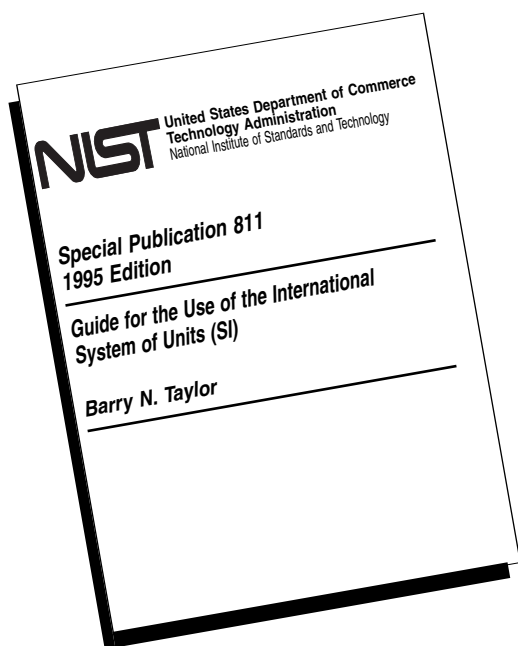
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The International System of Units (SI)

A Guide for the Use of the Modern Metric System

NIST Special Publication 811, 1995 Edition



Uncertain about the International System of Units (universally abbreviated SI), the modern metric system used throughout the world? Do you need to know the proper way to express the results of measurements and the values of quantities in units of the SI? Do you need to know the NIST policy on the use of the SI? Then you need the 1995 Edition of the National Institute of Standards and Technology Special Publication 811, *Guide for the Use of the International System of Units (SI)*.

The 1995 Edition of the National Institute of Standards and Technology Special Publication 811, *Guide for the Use of the International System of Units (SI)*, by Barry N. Taylor, is now available.

The 1995 Edition of SP 811 corrects a number of misprints in the 1991 Edition, incorporates a significant amount of additional material intended to answer frequently asked questions concerning the SI and SI usage, and updates the bibliography. The added material includes a check list for reviewing the consistency of written documents with the SI. Some changes in format have also been made in an attempt to improve the ease of use of SP 811.

The topics covered by SP 811 include:

- NIST policy on the use of the SI in NIST publications.
- Classes of SI units, those SI derived units that have special names and symbols, and the SI prefixes that are used to form decimal multiples and submultiples of SI units.
- Those units outside the SI that may be used with the SI and those that may not.
- Rules and style conventions for printing and using quantity symbols, unit symbols, and prefix symbols, and for spelling unit names.
- Rules and style conventions for expressing the results of measurements and the values of quantities.
- Definitions of the SI base units.
- Conversion factors for converting values of quantities expressed in units that are mainly unacceptable for use with the SI to values expressed mainly in units of the SI.
- Rounding numbers and rounding converted numerical values of quantities.

Single copies of the 84-page NIST SP 811, 1995 Edition, may be obtained by contacting the NIST Metric Program, 100 Bureau Drive, Stop 2000, Gaithersburg, MD 20899-2000; telephone: 301-975-3690; fax: 301-948-1416; email: metric_prg@nist.gov. NIST SP 811 is also available online at the NIST Web site entitled "NIST Reference on Constants, Units, and Uncertainty," physics.nist.gov/cuu.

Evaluating and Expressing the Uncertainty of Measurement Results



Uncertain about expressing measurement uncertainty? Do you need to know how NIST states the uncertainty of its measurement results and how you can implement their internationally accepted method in your own laboratory? Then you need the newly available 1994 edition of the National Institute of Standards and Technology Technical Note 1297, *Guidelines for Evaluating and Expressing the Uncertainty of NIST Measurement Results*.

The 1994 edition of the National Institute of Standards and Technology Technical Note 1297, *Guidelines for Evaluating and Expressing the Uncertainty of NIST Measurement Results*, by Barry N. Taylor and Chris E. Kuyatt is now available.

The 1994 edition of TN 1297 includes a new appendix—Appendix D—which clarifies and gives additional guidance on a number of topics related to measurement uncertainty, including the use of certain terms such as accuracy and precision. Very minor word changes have also been made in a few portions of the text of the 1993 edition in order to recognize the official publication in October 1993 by the International Organization for Standardization (ISO) of the *Guide to the Expression of Uncertainty in Measurement* on which TN 1297 is based. However, the NIST policy on measurement uncertainty, Statements of Uncertainty Associated with Measurement Results, which is reproduced as Appendix C of TN 1297, is unchanged.

It is expected that the 1994 edition of TN 1297 will be even more useful than its immediate predecessor, the 1993 edition, of which 10 000 copies were distributed worldwide.

Those United States readers who wish to delve into the subject of measurement uncertainty in greater depth may purchase a copy of the 100-page ISO *Guide* from the Sales Department of the American National Standards Institute (ANSI), 105-111 South State Street, Hackensack, NJ 07601. Copies may also be purchased from the ISO Central Secretariat, 1 rue de Varembe, Case postale 56, CH-1211 Genève 20, Switzerland.

Single copies of the 20-page TN 1297 may be obtained from the NIST Calibration Program, Building 820, Room 232, Gaithersburg, MD 20899-0001, telephone: 301-975-2002, fax: 301-948-3825.

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